

INFORMATION DISCLOSURE
CITATION

PTO-1449

ATTORNEY'S DKT NO.
015780-034APPLICATION NO.
09/632,631APPLICANT
Naulleau et al.FILING DATE
August 4, 2000GROUP
2877

U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE

FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation Yes No
<i>all</i>	WO92/2099	11-26-92	PCT			

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>rd</i>	Kim S-W, et al., "Lateral-shearing Interferometer Using Square Prisms for Optical Testing of Aspheric Lenses", Measurement Science and Technology, IOP Publishing, Bristol, GB, Vol. 9, July 1998, pages 1129-1136.

EXAMINER

DATE CONSIDERED

5/24/03

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

